Substitute Form PTO-1449 U.S. Department of Commerce Patent and Trademark Office Information Disclosure Statement by Applicant (Use several sheets if necessary) (37 CFR §1.98(b))						
		Applicant Rainer Butendeich et al.				
		Filing Date May 15, 2006	Group Art Unit 2814			

U.S. Patent Documents							
Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
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Other Documents (include Author, Title, Date, and Place of Publication)				
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AK Copy of First Office Action of Chinese Patent Application No. 200480018204.2, dated June				
	AL	K.L. Chang et al., "Effect of group II Impurity and group III native defect on disordering Cu-Pt type ordered structures In In ₃ (Al ₂ (Ag ₃) ₂) Players", <u>Journal of Applied Physics</u> , Vol. 92, No. 11, pp. 682-6589 (December 1, 2002)		
	AM	High Brightness Light Emitting Diodes, Semiconductors and Semimetals, Vol. 48, eds. G.B. Stringfellow, M.G. Crawford, Academic Press (1997), pp. 1-45, 65-83, and 149-178		
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Examiner Signature /Abul Kalam/	Date Considered	08/13/2008
EXAMINER: Initials citation considered. Draw line through citation if no next communication to applicant.	t in conformance and	not considered. Include copy of this form with